

**S1**. Microstructure of Ce<sub>20.0</sub>Pt<sub>40.0</sub>Al<sub>40.0</sub> (at.%) samples annealed at 250°C, 320°C, 550°C, 650°C, 700°C

**S2**. XRD patterns of Ce<sub>20.0</sub>Pt<sub>40.0</sub>Al<sub>40.0</sub> (at.%) samples annealed at different temperatures (ag). XRD patterns in the 25.5 – 36.5  $2\theta$  range showing dependence of FWHM on the annealing temperature (h).







Heating DTA thermogram of CePt<sub>2</sub>Al<sub>2</sub> sample annealed at 550 °C.



S4. Structural transition of the low-temperature orthorhombic CePt<sub>2</sub>Al<sub>2</sub> to the high-temperature tetragonal modification. XRD patterns at 220, 230, 240, 250, 260, 270, 280, 290, 300, 310, 320°C (a); a projection of XRD patterns (b).

		_ ll_ll_		320°C
				310°C
				300°C
				290°C
1				280°C
				270°C
				260°C
				250°C
l				240°C
				230°C
				220°C
1.0	5.0	9.0	13.0 17.0 2Theta [°]	21.0

## a)

Projection of XRD patterns at 220, 230, 240, 250, 260, 270, 280, 290, 300, 310, 320°C(b).

0.0	200.0	400.0	600.0	800.0 Absolute Intensity	1000.0	1200.0	1400.0	
320° <mark>C</mark>								
310°C								
290°C								
280°C								
260°C								
250°C 240°C								
230°C								